

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 03500.010106.5		APPLICATION NO. NOT YET ASSIGNED	
APPLICANT TOSHIKAZU OHNISHI ET AL.							
FILING DATE FILED HEREWITH						GROUP 2879	

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	6,348,761 B1	2/02	Nomura et al.	313	495	6/94	
	4,949,019	8/90	Isaka et al.	445	6		
	5,066,883	11/91	Yoshioka et al.	313	309		
	5,006,883	11/91	Yoshioka et al.	313	309		
	4,954,744	8/90	Suzuki et al.	313	336X		
	5,285,129	2/94	Takeda et al.	313	336X		
	5,256,936	12/89	Itoh et al.	313	309X		
	5,141,460	8/92	Jaskie et al.	313	309X		

FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		
0523702A1	1/93	EPO			Abstract		
1283749A	12/89	JAPAN			Abstract		
A1309242	12/89	JAPAN			No		
536731A1	1/93	EPO					
1-309242	12/89	JAPAN			Translation		
0 299 461	1/89	EPO					

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OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)			
		"Metal Influence on Switching MIM Diodes", H. Pagnia, et al., Phys. Stat. Sol. (a), 111, 387 (1989)	
		"Scanning Tunnelling Microscopic Investigations of Electroformed Planar Metal-Insulator-Metal Diodes," H. Pagnia, N. Sotnik and W. Wirth, Int. J. Electronics, Vol. 69, No. 1, 25-32 (1990)	
		"Energy Distribution of Emitted Electrons from Electroformed MIM Structures: The Carbon Island Model," M. Bischoff, H. Pagnia and J. Trickl, Int. J. Electronics, Vol. 73, No. 5, 1009-1010 (1992)	
		"Thin Film Handbook," Committee 131 of Japanese Society for the Promotion of Art and Science	
		"On the Electron Emission from Evaporated Thin Au Films," M. Bischoff, R. Holzer and H. Pagnia, Physics Letters, Vol. 62A, No. 7 (October 3, 1977)	
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		"Water-Influenced Switching in Discontinuous Au Film Diodes," R. Muller and H. Pagnia, Materials Letters, Vol. 2, No. 4A, 283-285 (March 1984)	
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		"Influence of Gas Composition on Regeneration in Metal/Insulator/Metal Diodes," M. Borbonus, H. Pagnia and N. Sotnik, Thin Solid Films, Vol. 151, 333-342 (1987)	
		"Prospects for Metal/Non-Metal Microsystems: Sensors, Sources and Switches," H. Pagnia, Int. J. Electronics, Vol. 73, No. 5, 319-825 (1992)	
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		G. Dittner, "Electrical Conduction and Electron Emission of Discontinuous Thin Films," Thin Solid Films, 9, (1972) pp. 317-328
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		M. Araki, "Electroforming and Electron Emission of Carbon Thin Films," J. Vac. Soc. Japan, 26, (1983) pp. 22-29
		"Carbon-Nanoslit Model for the Electroforming Process in MIM Structures," M. Bischoff, Int. J. Electronics, Vol. 70, No. 3, 491-498 (1991)
		Patent Abstracts of Japan, vol. 14, no. 1 08 (E-896) (4051), Feb 27, 1990
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